


Prüfbericht - Nr.: 50087418 001 <i>Test Report No.</i>		Seite 1 von 11 <i>Page of</i>	
Auftraggeber: <i>Client:</i>	Oi Electric Co., Ltd. 7-3-16, Kikuna, Kohoku-ku, Yokohama, 222-0011, Japan		
Gegenstand der Prüfung: <i>Test item:</i>	MIRUECOMini		
Bezeichnung: <i>Identification:</i>	OiNET-652	Serien-Nr.: <i>Serial No.</i>	500610100050
Wareneingangs-Nr.: <i>Receipt No.:</i>	A000593198-001	Eingangsdatum: <i>Date of receipt:</i>	2017-07-27
Zustand des Prüfgegenstandes bei Anlieferung: <i>Condition of test item at delivery:</i>	Test item completed and undamaged		
Prüfört: <i>Testing location:</i>	TÜV Rheinland Japan Ltd. Global Technology Assessment Center 4-25-2 Kita-Yamata, Tsuzuki-ku Yokohama 224-0021, Japan		
Prüfgrundlage: <i>Test specification:</i>	OpenADR 2.0b Certification Test Specification Version 1.1.0		
Prüfergebnis: <i>Test Result:</i>	Der Prüfgegenstand entspricht oben genannter Prüfgrundlage(n). <i>The test item passed the test specification(s).</i>		
Prüflaboratorium: <i>Testing Laboratory:</i>	TÜV Rheinland Japan Ltd. Global Technology Assessment Center 4-25-2 Kita-Yamata, Tsuzuki-ku Yokohama 224-0021, Japan		
geprüft / tested by:	kontrolliert / reviewed by:		
2017-08-23, Atsuhiko Endo 	2017-08-25, Tam Tran Thanh 		
Datum <i>Date</i>	Unterschrift <i>Signature</i>	Datum <i>Date</i>	Unterschrift <i>Signature</i>
Sonstiges / Other Aspects:			
Abkürzungen: OK, Pass = entspricht Prüfgrundlage Fail = entspricht nicht Prüfgrundlage N/A = nicht anwendbar		Abbreviations: OK, Pass = passed Fail = failed N/A = not applicable	
<p>Dieser Prüfbericht bezieht sich nur auf den o.g. Prüfgegenstand und darf ohne Genehmigung der Prüfstelle nicht auszugsweise vervielfältigt werden. Dieser Bericht berechtigt nicht zur Verwendung eines Prüfzeichens. This test report relates to the a. m. test item. Without permission of the test center this test report is not permitted to be duplicated in extracts. This test report does not entitle to carry any test mark on this or similar products.</p>			

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1. General Product Information

1.1 Client Information

Company name:	see page 1
Address:	see page 1
Contact Person:	Toshiyuki Nakane
Phone:	+81-45-286-2452
Fax:	N/A
Email:	nakane_toshiyuki@ooi.co.jp

1.2 General SUT Information

Serial number:	see page 1
Hardware version:	N/A
Firmware version:	1.00A

1.3 General EUT Description

Equipment under test:	see page 1
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1.4 Type of Product

Product type:	VEN
OpenADR profile:	2.0b
Mode:	Pull
Transport:	Simple HTTP
Security:	Standard Security

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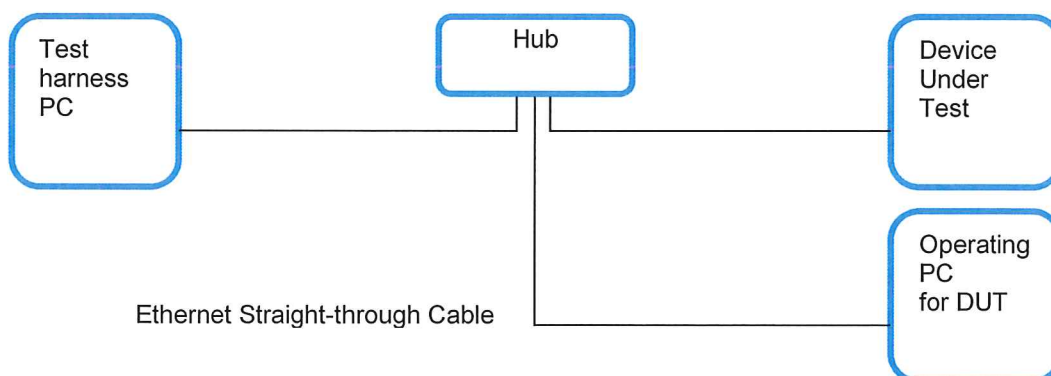
2. Testing Laboratory

Company name: TÜV Rheinland Japan Ltd.
Address: see page 1

2.1 Test Equipment

Instrument	Manufacturer	Model Number	Version/Errata
Test tool	QualityLogic	OpenADR2.0bCertTest	1.1.0

2.2 Test Setup



2.3 Environmental Conditions

Temperature: 19°C to 25°C
Relative humidity: 25% to 75%
Testing date: July 27-28, 2017
August 23, 2017

3. Information about Test Results

3.1 General

Documentation of tested devices and results:

The complete set of measurement results is stored at the TÜV Rheinland Japan Ltd. test laboratory and is available on demand.

Interpretation of test results:

The results of the inspection are described on the following pages. "Pass" in the test result list of this test report means the performed test according to the test specification was verified and that the tested device is conformant to the specification. "Fail" means that the performed test according to the test specification was verified and the tested device is not conformant to the specification or that test didn't run to completion because the tested device is not conformant to the specification. "N/A" means the test cases are optional and/or not applicable to the tested device.

4. Test Results

4.1 VEN Pull Tests

4.1.1 EiRegisterParty Service

No.	Test Case Name	Date	Result	Log
1	N1_0010_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_150347_406.txt
2	N1_0015_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_152405_729.txt
3	N1_0020_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_150715_649.txt
4	N1_0025_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_153540_900.txt
5	N1_0030_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_153157_767.txt
6	N1_0040_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_154033_794.txt
7	N1_0050_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_154813_188.txt
8	N1_0060_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_155157_401.txt
9	N1_0065_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_160257_007.txt
10	N1_0070_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_160548_145.txt
11	N1_0080_TH_VTN_1	July 27 2017	N/A	TraceLog_072717_154402_511.txt

4.1.2 EiOpt Service

No.	Test Case Name	Date	Result	Log
1	P1_2010_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_163626_499.txt
2	P1_2015_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_163902_818.txt
3	P1_2020_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_164241_595.txt
4	P1_2030_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_164503_139.txt
5	P1_2040_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_164941_834.txt
6	P1_2050_TH_VTN_1	July 27 2017	N/A	TraceLog_072717_165404_967.txt

4.1.3 EiReport Service

No.	Test Case Name	Date	Result	Log
1	R1_3010_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_133901_109.txt
2	R1_3020_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_134042_670.txt
3	R1_3025_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_134251_445.txt
4	R1_3027_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_134642_382.txt
5	R1_3030_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_135146_291.txt
6	R1_3040_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_135423_212.txt
7	R1_3045_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_135625_949.txt
8	R1_3050_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_135841_624.txt
9	R1_3060_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_140028_403.txt
10	R1_3070_TH_VTN_1	-	N/A	-
11	R1_3080_TH_VTN_1	-	N/A	-
12	R1_3090_TH_VTN_1	-	N/A	-
13	R1_3100_TH_VTN_1	-	N/A	-
14	R1_3120_TH_VTN_1	-	N/A	-
15	R1_3130_TH_VTN_1	-	N/A	-
16	R1_3140_TH_VTN_1	-	N/A	-
17	R1_3150_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_132434_829.txt
18	R1_3160_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_132629_893.txt
19	R1_3170_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_133103_778.txt
20	R1_3180_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_133330_037.txt
21	R1_3190_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_133546_333.txt

4.1.4 EiEvent Service

No.	Test Case Name	Date	Result	Log
1	E1_1010_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_165811_252.txt
2	E1_1020_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_170006_521.txt
3	E1_1025_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_170453_020.txt
4	E1_1027_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_170720_360.txt
5	E1_1030_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_171424_149.txt
6	E1_1040_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_171650_753.txt
7	E1_1050_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_172107_764.txt
8	E1_1055_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_172342_146.txt
9	E1_1060_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_172617_000.txt
10	E1_1065_TH_VTN_1	July 27 2017	N/A	TraceLog_072717_172836_999.txt
11	E1_1070_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_173012_795.txt
12	E1_1080_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_173212_626.txt
13	E1_1090_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_173528_289.txt

4.1.5 EiEvent Ported A Profile

No.	Test Case Name	Date	Result	Log
1	A_E1_0020_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_095633_588.txt
2	A_E1_0040_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_095906_550.txt
3	A_E1_0060_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_100224_726.txt
4	A_E1_0070_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_100627_769.txt
5	A_E1_0082_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_101157_132.txt
6	A_E1_0086_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_102848_300.txt
7	A_E1_0090_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_103103_424.txt
8	A_E1_0092_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_103427_014.txt
9	A_E1_0094_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_103751_902.txt
10	A_E1_0096_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_104016_497.txt
11	A_E1_0098_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_104148_106.txt
12	A_E1_0100_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_104422_873.txt
13	A_E1_0102_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_104735_998.txt
14	A_E1_0104_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_105032_161.txt
15	A_E1_0110_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_105315_251.txt
16	A_E1_0130_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_105553_229.txt
17	A_E1_0180_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_110013_873.txt
18	A_E1_0190_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_110730_029.txt
19	A_E1_0200_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_143657_508.txt
20	A_E1_0210_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_113042_659.txt
21	A_E1_0220_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_114001_648.txt
22	A_E1_0230_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_115221_936.txt
23	A_E1_0240_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_130631_807.txt
24	A_E1_0250_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_131627_572.txt
25	A_E1_0260_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_132500_563.txt
26	A_E1_0262_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_134855_049.txt
27	A_E1_0267_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_141300_224.txt
28	A_E1_0268_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_143227_528.txt
29	A_E1_0270_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_145401_446.txt
30	A_E1_0280_TH_VTN_1	August 23 2017	PASS	TraceLog_082317_140416_503.txt
31	A_E1_0285_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_151444_307.txt
32	A_E1_0300_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_151819_601.txt
33	A_E1_0310_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_152143_620.txt
34	A_E1_0340_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_152512_234.txt
35	A_E1_0345_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_152825_258.txt
36	A_E1_0360_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_153131_492.txt
37	A_E1_0370_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_150441_282.txt
38	A_E1_0390_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_153553_797.txt
39	A_E1_0392_TH_VTN_1	July 28 2017	PASS	TraceLog_072817_153756_580.txt

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4.1.6 General Tests

No.	Test Case Name	Date	Result	Log
1	G1_4005_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_140654_404.txt
2	G1_4007_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_141121_389.txt
3	G1_4010_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_140950_255.txt
4	G1_4015_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_142304_539.txt
5	G1_4030_TH_VTN_1	July 27 2017	PASS	TraceLog_072717_142826_794.txt

Appendix A: Remarks and References

Log files for the executed test cases are provided in the electronic format.

List of all executed tests with links to the log files is located in the "logfile.xml" which could be opened in any web-browser (Internet Explorer is recommended).

Appendix B: Photos



Photo 1: Test Steup

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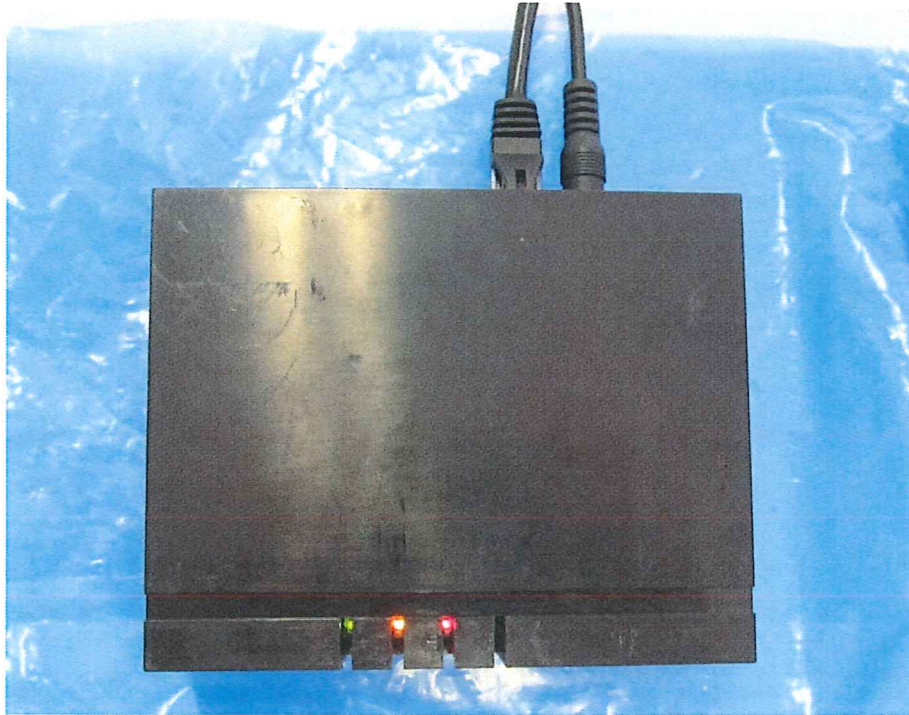


Photo 2: Device Under Test



Photo 3: Identification / Serial No.